

AMENDMENT TO THE CLAIMS

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Claims 1-17 (canceled).

18. (new) A power tester apparatus for testing an electronic device, the device configured to operate using a constant power supply voltage, the apparatus comprising:

a power source supplying the constant power supply voltage;  
a connector coupled to the power source, the connector adapted to connect the constant power supply voltage to a power supply input on the electronic device;

circuitry configured to introduce disturbances into the constant power supply voltage applied to the electronic device, a disturbance configured to simulate an unexpected change in a nominal power supply voltage;

wherein the disturbances introduced into the constant power supply voltage applied to the electronic device are controllable.

19. (new) The apparatus of claim 18 wherein the disturbance is a rising pulse having a maximum voltage which is controllable.

20. (new) The apparatus of claim 18 wherein the disturbance is a low-going pulse having a minimum voltage being less than the voltage.

21. (new) The apparatus of claim 18 wherein the constant power supply voltage is selected from the group of voltages consisting of +5 VDC and +12 VDC.

22. (new) The apparatus of claim 18 further comprising an additional power source supplying an additional voltage wherein the additional power source is adapted to connect the additional voltage to an additional connector.

23. (new) The apparatus of claim 22 wherein the additional voltage is + 24 VDC.

24. (new) The apparatus of claim 18 including a manually operated user interface used to control the disturbances.

25. (new) The apparatus of claim 18 wherein the disturbance is at least one pulse having a duration and a magnitude which are controllable.

26. (new) The apparatus of claim 18 wherein the disturbance is a plurality of pulses and a frequency and a number of pulses in the plurality of pulses are controllable.

27. (new) The apparatus of claim 18 wherein the disturbance comprises a voltage sequence applied during powering up of the electronic device.

28. (new) A method for testing an electronic device of the type which is powered by a constant power supply voltage, the method comprising:

supplying the constant powering supply voltage from a voltage source;

coupling the constant power supply voltage to a connector, the connector adapted to connect the constant power supply voltage to a power supply input of the electronic device;

introducing a disturbance into the constant power supply voltage applied to the power supply input of the electronic device; and

controlling the disturbance introduced into the constant power supply voltage applied to the power supply to

simulate an unexpected change in a nominal power supply voltage.

29. (new) The method of claim 28 wherein the disturbance is a rising pulse having a maximum voltage which is controllable.

30. (new) The method of claim 28 wherein the disturbance is a low-going pulse voltage which is controllable.

31. (new) The method of claim 28 wherein the nominal voltage is selected from the group of voltages consisting of +5 VDC and +12 VDC.

32. (new) The method of claim 28 further comprising:  
supplying an additional voltage from an additional power source, the additional power source adapted to connect the additional voltage to an additional connector.

33. (new) The method of claim 32 wherein the additional voltage is + 24 VDC.

34. (new) The method of claim 28 including receiving control parameters from the user interface.

35. (new) The method of claim 28 wherein the disturbance is a pulse having a controllable duration and a controllable magnitude.

36. (new) The method of claim 28 wherein the disturbance is a plurality of pulses and a number of the plurality of pulses are controllable.

37. (new) The method of claim 28 further including providing a 0

VDC voltage for a preselected duration of time after the voltage is coupled to the connector.